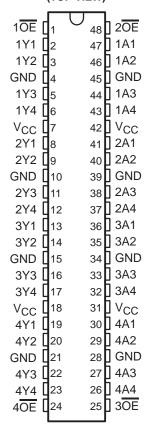
- Members of the Texas Instruments Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V<sub>CC</sub> and GND Pin Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings

#### description

The SN54ACT16244 and 74ACT16244 are 16-bit buffers/line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. They can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. The devices provide true outputs and symmetrical  $\overline{OE}$  (active-low) output-enable inputs.

SN54ACT16244 . . . WD PACKAGE 74ACT16244 . . . DGG OR DL PACKAGE (TOP VIEW)



The 74ACT16244 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ACT16244 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74ACT16244 is characterized for operation from –40°C to 85°C.

# FUNCTION TABLE (each driver)

INP	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z

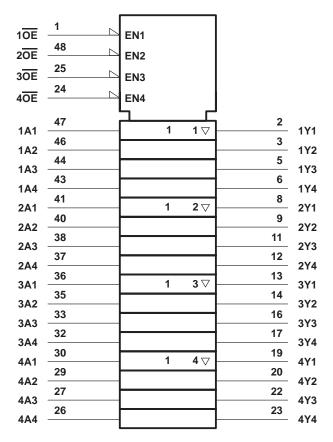


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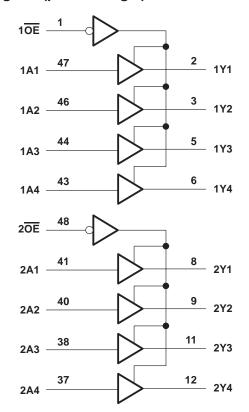
### logic symbol<sup>†</sup>

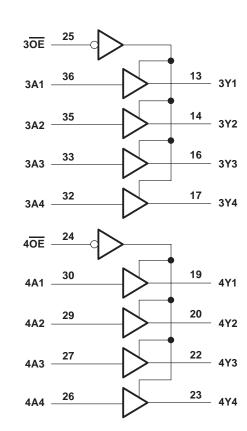


<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



### logic diagram (positive logic)





### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through V <sub>CC</sub> or GND	±400 mA
Maximum power dissipation at $T_A = 55^{\circ}$ C (in still air) (see Note 2): DGG pack	kage 0.85 W
DL packag	ge 1.2 W
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.



## SN54ACT16244, 74ACT16244 **16-BIT BUFFERS/LINE DRIVERS WITH 3-STATE OUTPUTS**

SCAS116B - MARCH 1990 - REVISED APRIL 1996

### recommended operating conditions (see Note 3)

		SN54ACT16244		74ACT	UNIT	
		MIN	MAX	MIN	MAX	UNIT
Vсс	Supply voltage (see Note 4)	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
VIL	Low-level input voltage		0.8		0.8	V
٧ <sub>I</sub>	Input voltage	0	VCC	0	VCC	V
Vo	Output voltage	0	Vcc	0	VCC	V
IOH	High-level output current		-24		-24	mA
loL	Low-level output current		24		24	mA
Δt/Δν	Input transition rise or fall rate	0	10	0	10	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTES: 3. Unused inputs should be tied to V<sub>CC</sub> through a pullup resistor of approximately 5 kΩ or greater to prevent them from floating.

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS	V	T,	Δ = 25°C	;	SN54AC	Γ16244	74ACT16244		UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	Jan 50 44	4.5 V	4.4			4.4		4.4		
	I <sub>OH</sub> = -50 μA	5.5 V	5.4			5.4		5.4		
Vou	I <sub>OH</sub> = -24 mA	4.5 V	3.94			3.7		3.8		٧
VOH	10H = -24 IIIA	5.5 V	4.94			4.7		4.8		V
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	V
		5.5 V			0.1		0.1		0.1	
Va.	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44	
VOL		5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μΑ
loz	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5 V			±0.5		±10		±5	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		160		80	μΑ
∆lCC <sup>‡</sup>	One input at 3.4 V, Other inputs at GND or V <sub>CC</sub>	5.5 V			0.9		1		1	mA
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4.5						pF
Co	V <sub>O</sub> = V <sub>CC</sub> or GND	5 V		13.5						pF

Thot more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



<sup>4.</sup> All V<sub>CC</sub> and GND pins must be connected to the proper voltage supply.

<sup>‡</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V<sub>CC</sub>.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (INPUT) (OUTPUT)	_	T,	<b>Վ = 25°</b> C	;	MIN	MAX	UNIT
		(0011 01)	MIN	TYP	MAX			
t <sub>PLH</sub>	Α Α	Υ -	4	6.5	8.5	3	10.3	no
<sup>t</sup> PHL			3.4	6.3	8.7	3.4	10.1	ns
<sup>t</sup> PZH	ŌĒ	V	3	5.8	8.1	3	10.5	no
t <sub>PZL</sub>		T	3.7	6.7	9.3	3.7	11	ns
<sup>t</sup> PHZ	ŌĒ		5.4	8.1	11.5	5.4	13	ns
t <sub>PLZ</sub>		1	5	7.5	9.5	5	10.9	115

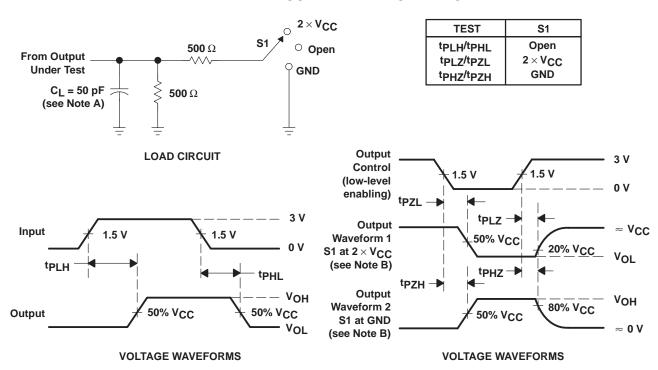
switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		TO (OUTPUT)						
PARAMETER	FROM TO (INPUT) (OUTPUT)		T <sub>A</sub> = 25°C			MIN	MAN	UNIT
		(0011 01)	MIN	TYP	MAX	I	MAX	
<sup>t</sup> PLH	Α Α	V	4	6.5	8.5	4	9.4	20
t <sub>PHL</sub>		Ĭ	3.4	6.3	8.7	3.4	9.5	ns
<sup>t</sup> PZH	- ŌĒ	V	3	5.8	8.1	3	8.9	ne
t <sub>PZL</sub>		ı	3.7	6.7	9.3	3.7	10.3	ns
t <sub>PHZ</sub>	- ŌĒ	V	5.4	8.1	10.3	5.4	11.3	ne
<sup>t</sup> PLZ		'	5	7.5	9.5	5	10.3	ns

operating characteristics,  $V_{CC}$  = 5 V,  $T_A$  = 25°C

PARAMETER			TEST COI	TYP	UNIT	
C <sub>pd</sub> Power dissipa	Dower discipation conscitance	Outputs enabled	C 50 pF	f = 1 MHz	39	nE.
	Power dissipation capacitance	Outputs disabled	$C_L = 50 \text{ pF},$		11	pΕ

### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ .
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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